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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/727,775	KLEIN ET AL.	
Examiner	Art Unit	
Christopher B. Shin	2181	

SEARCHED			
Class	Subclass	Date	Examiner
710	1,36-45	2/28/2006	CBS
710	72-74	2/28/2006	CBS
711	100-114	2/28/2006	CBS
711	161-164	2/28/2006	CBS
711	170-174	2/28/2006	CBS
707	1	2/28/2006	CBS
707	200-206	2/28/2006	CBS

INTERFERENCE SEARCHED			
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710	36,72	6/21/2006	CBS
707	1,205	6/21/2006	CBS
711	112,161	6/21/2006	CBS
711.	/170	6/21/2006	CBS

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
PLUS	2/28/2006	CBS
PALM for Double Patenting	2/28/2006	CBS
EAST (US PGPUB, USPAT, USOCR, EPO, JPO, DERWENT, IBM TDB)	2/28/2006	CBS